


<b>Search Notes</b> 	<b>Application/Control No.</b> 10751436	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> CongVan Tran	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
370	401, 328, 351	3/12/08	CT
455	433	3/12/08	CT

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner